

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

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APPLICANT

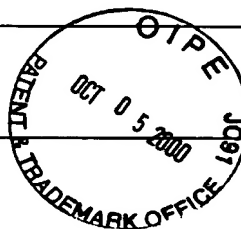
T. FRANK WANG

FILING DATE

JULY 3, 2000

GROUP ART UNIT

1765

LIST OF REFERENCES CITED BY APPLICANT  
(Use Several Sheets if Necessary)

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>h</i>	AA	4,923,562	5/8/90	JUCHA ET AL.			
<i>h</i>	AB	5,100,505	3/31/92	CATHEY, JR.			
<i>h</i>	AC	5,143,866	9/1/92	MATSUTANI			
<i>h</i>	AD	5,609,775	3/11/97	LIU			
<i>h</i>	AE	5,772,906	6/30/98	ABRAHAM			
<i>h</i>	AF	5,846,443	12/8/98	ABRAHAM			
<i>h</i>	AG	5,853,602	12/29/98	SHOJI			
<i>h</i>	AH	5,952,244	9/14/99	ABRAHAM, ET AL.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO
	AI				
	AJ				
	AK				
	AL				
	AM				
	AN				

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>h</i>	AO	DAVID A. SHUMATE, ET AL., "DEVELOPMENT OF A TiW PLASMA ETCH PROCESS USING A MIXTURE EXPERIMENT AND RESPONSE SURFACE OPTIMIZATION", IEEE TRANSACTIONS ON SEMICONDUCTOR MANUFACTURING, VOL. 9 NO. 3, AUGUST 1996.
	AP	
	AQ	

EXAMINER

*Theresa A. - for*

DATE CONSIDERED

10/20/01

\*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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GROUP 1700